

Annex with Paragraph As Amended:

Fig. 21 shows a block diagram of a memory 200 with a built-in self test circuit according to a third embodiment of the present invention. Memory 200 with a built-in self test circuit of the third embodiment is similar to memory 20 with a built-in self test circuit of Fig. 2, provided that input/output and BIST write/determination circuit 32 is replaced with an input/output and BIST write/determination circuit 210 functioning to provide the generated data (EXPDM) from ALPG 54 directly to tester 22.